

GDAŃSK UNIVERSITY

Subject card

Subject name and code	Design of VLSI Circuits, PG_00048579							
Field of study	Electronics and Telec	communication	s					
Date of commencement of studies	February 2024		Academic year of realisation of subject		2023/2024			
Education level	second-cycle studies		Subject group		Optional subject group Subject group related to scientific research in the field of study			
Mode of study	Full-time studies		Mode of delivery			at the university		
Year of study	1		Language of instruction			English		
Semester of study	1		ECTS credits		1.0			
Learning profile	general academic profile		Assessment form		assessment			
Conducting unit	Department of Microe	electronic Syste	ems -> Faculty	of Electronics,	Teleco	mmunic	ations and Ir	formatics
Name and surname	Subject supervisor		dr hab. inż. Anna Pietrenko-Dąbrowska					
of lecturer (lecturers)	Teachers		dr hab. inż. Anna Pietrenko-Dąbrow			ska		
Lesson types and methods	Lesson type	Lecture	Tutorial Laboratory Project		t	Seminar	SUM	
of instruction	Number of study hours	15.0	0.0	0.0	0.0		0.0	15
	E-learning hours inclu	uded: 0.0						
Learning activity and number of study hours	Learning activity	Participation i classes incluc plan		Participation i consultation h	ticipation in sultation hours		tudy	SUM
	Number of study hours	15		2.0		8.0		25
Subject objectives	Introduction to design generation of their top		ts with emphas	is on discussio	n of alg	orithmic	c approaches	used for
Learning outcomes	Course outcome		Subject outcome		Method of verification			
	[K7_K02] is ready to provide critical evaluation of received content and to acknowledge the importance of knowledge in solving cognitive and practical problems		The student can perform analysis of the discussed algorithmic approaches in terms oftheir advantages and disadvantages in the constext of VLSI circuits design.		[SK2] Assessment of progress of work			
	[K7_W03] Knows and understands, to an increased extent, the construction and operating principles of components and systems related to the field of study, including theories, methods and complex relationships between them and selected specific issues - appropriate for the curriculum.		The student is acquainted with selected topics related to VLSI circuit design, as well as understands basic design steps and their significance from the perspective of topology generation.		[SW3] Assessment of knowledge contained in written work and projects			
	[K7_U07] can apply advanced methods of process and function support, specific to the field of study		The student can exploit algorithmic approaches for solving tasks resulting from the selected stages of VLSI circuits design		[SU2] Assessment of ability to analyse information [SU1] Assessment of task fulfilment			
	[K7_W04] Knows and understands, to an advanced extent, the principles, methods and techniques of programming and the principles of computer software development or programming devices or controllers using microprocessors or programmable elements or systems specific to the field of study, and organisation of systems using computers or such devices		The student is acquainted with algorithms utilized in VLSI circuits design (objective functions, working principles, constraints, etc.) and can select appropriate algorithm for solving problems at the given design stage.		[SW3] Assessment of knowledge contained in written work and projects			

	1 Introduction to V/I SI airquite de	aign:														
Subject contents	1. historical perspective,	 Introduction to VLSI circuits design: historical perspective. 														
	2. development of integrated circuits,															
	3. challenges and future prospects															
	 Design of VLSI circuits: hierarchical design approach, 															
	2. photolithography,															
	3. rules for layout generation,															
	 design styles, layout design steps, 															
	packages used for VLSI of	ircuits,														
	7. problem complexity															
	 Introduction to graph theory Matrix-based representation 	ons of graphs														
	2. Hipergraphs	0.1														
	3. Graph-based approximati															
	 Selected graph-based algorithms Partitioning 															
	1. The problem of partitioning at different layers of abstraction															
	2. Challenges related to circuit partitioning															
	 Selected partitioning algorithms Floorplanning 															
	 The role of floorplanning in hierarchical design process Problem definition and objective functions Cluster growth and linear ordering algorithms Simulated annealing and data representation schemes 															
									5. Calculation of size							
									6. Analytical approach to floorplanning							
	 Floorplanning and routing – discussion Placement 															
	1. Problem definition, objective functions, and complexity															
	2. Solution approaches to placement															
	 Linearization techniques The problem of modules overlapping and related constraints 															
	Dealing with conflicts – le	 The problem of modules overlapping and related constraints Dealing with conflicts – legalization 														
	6. Detailed placement and related algorithms															
	 Routing Problem definition, constraints, and routing models 															
		2. Selected routing algorithms (maze, line-search, A*-search)														
			al and parallel approaches to the prob	lem												
	 Detailed routing – selecte Full-chip routing – hierarc 															
	 Full-chip routing – hierarchical and multi-level approaches Modern challenges in the context of routing (signal integrity, fabrication, reliability) 															
	8. Synthesis of clock and power networks for VLSI															
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	 Review of clock signal ne 	networks for VLSI works														
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Example issues/ example questions/ tasks being completed	
Work placement	Not applicable